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# **FDT86102LZ** N-Channel PowerTrench<sup>®</sup> MOSFET 100 V, 6.6 A, 28 m $\Omega$

### Features

- Max  $r_{DS(on)} = 28 \text{ m}\Omega \text{ at } V_{GS} = 10 \text{ V}, I_D = 6.6 \text{ A}$
- Max r<sub>DS(on)</sub> = 38 mΩ at V<sub>GS</sub> = 4.5 V, I<sub>D</sub> = 5.5 A
- HBM ESD protection level > 6 kV typical (Note 4)
- Very low Qg and Qgd compared to competing trench technologies
- Fast switching speed
- 100% UIL Tested
- RoHS Compliant

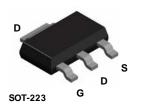


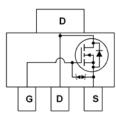
# **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench<sup>®</sup> process that has been especially tailored to minimize the on-state resistance and switching loss. G-S zener has been added to enhance ESD voltage level.

# Applications

- DC-DC conversion
- Inverter
- Synchronous Rectifier





### MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units		
V <sub>DS</sub>	Drain to Source Voltage			100	V		
V <sub>GS</sub>	Gate to Source Voltage			±20	V		
	Drain Current -Continuous			6.6	•		
D	-Pulsed			40	— A		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	84	mJ		
D	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.2	w		
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1b)	1.0	vv		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C		

### **Thermal Characteristics**

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	(Note 1)	12	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	55	C/vv

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
86102LZ	FDT86102LZ	SOT-223	13 "	12 mm	2500 units

# FDT86102LZ N-Channel PowerTrench<sup>®</sup> MOSFET

Symbol	Parameter	Test Conditions	Min	Тур	Мах	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0 \ V$	100			V
$\Delta BV_{DSS}$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		70		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μA
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μA
On Chara	cteristics					
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250 \ \mu A$	1.0	1.4	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$ , referenced to 25 °C		-6		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6.6 A		22	28	
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 5.5 A		27	38	mΩ
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6.6 A, T <sub>J</sub> = 125 °C		36	46	-
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 6.6 A		26		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	V 50.V.V. 0.V.		1118	1490	pF
C <sub>oss</sub>	Output Capacitance	── V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, f = 1MHz		181	245	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			7.5	15	pF
R <sub>g</sub>	Gate Resistance			0.5		Ω
Switching	g Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time			6.6	14	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 6.6 A,		1.9	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		19	31	ns
t <sub>f</sub>	Fall Time			2.2	10	ns
Q <sub>g(TOT)</sub>	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V		17	25	nC
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V} \text{ V}_{DD} = 50 \text{ V},$		8.3	12	
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = 6.6 A		2.6		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge			2.2		nC

### **Drain-Source Diode Characteristics**

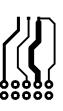
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 6.6 A$	(Note 2)	0.82	1.3	V
		$V_{GS} = 0 V, I_{S} = 1 A$	(Note 2)	0.68	1.2	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 6.6 A, di/dt = 100 A/μs		40	64	ns
Q <sub>rr</sub>	Reverse Recovery Charge			36	58	nC

NOTES:

1.  $R_{0JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{0JC}$  is guaranteed by design while  $R_{0CA}$  is determined by the user's board design.



a) 55 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper

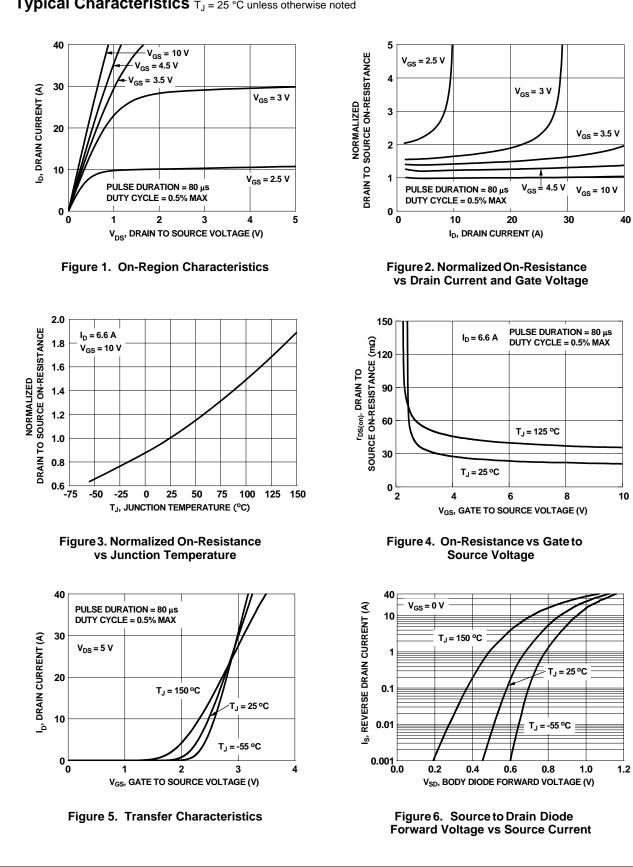


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b) 118 °C/W when mounted on a minimum pad of 2 oz copper

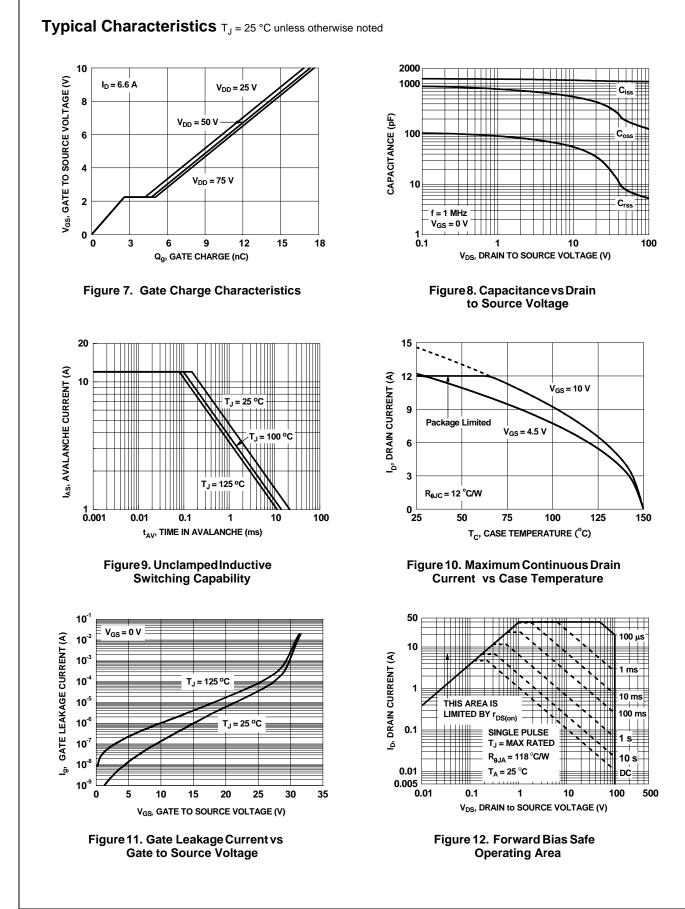
Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0 %.</li>
Starting T<sub>J</sub> = 25 °C, L = 1 mH, I<sub>AS</sub> = 13 A, V<sub>DD</sub> = 90 V, V<sub>GS</sub> = 10 V.
The diode connected between gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

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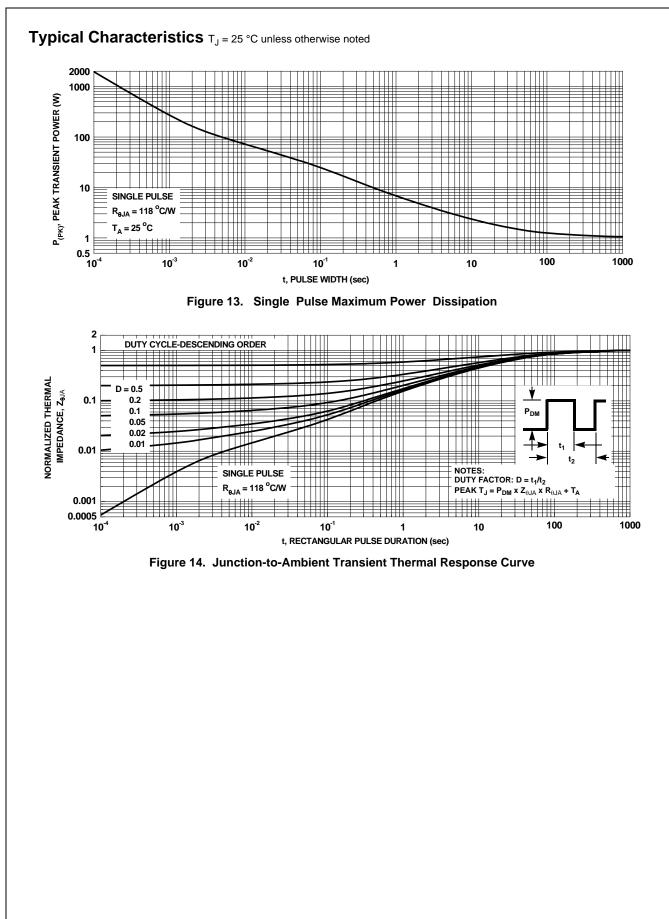


## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

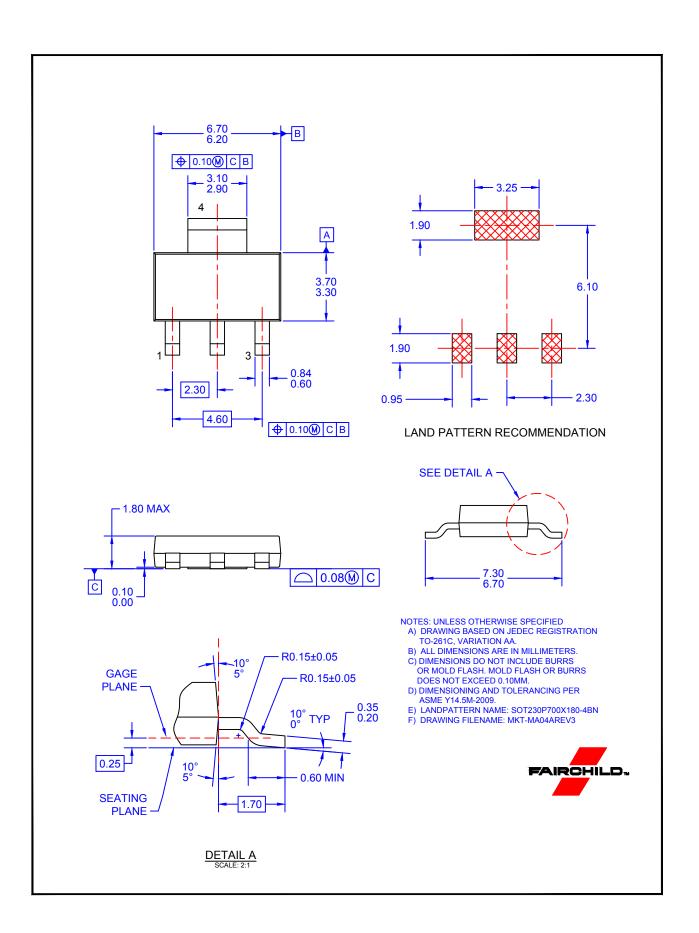




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